Scaling Al with Photonic Interconnects: Integration and Manufacturability

Jessie Rosenberg
Director of Laser Development, Lightmatter



JIGHTMATTER

A decade of AI breakthroughs

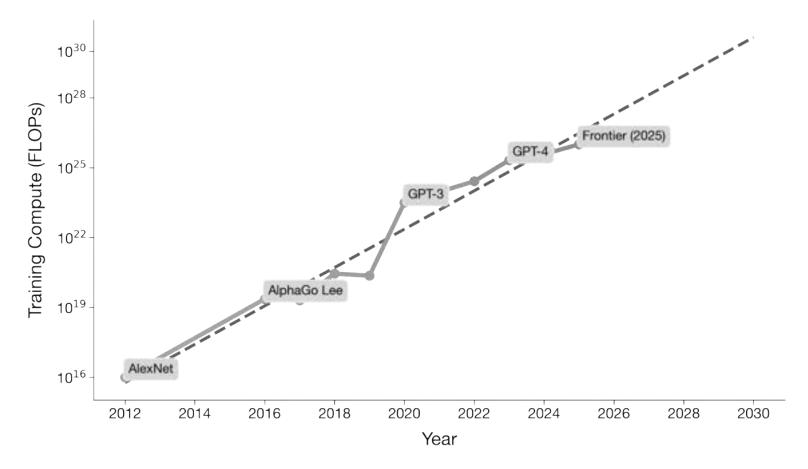




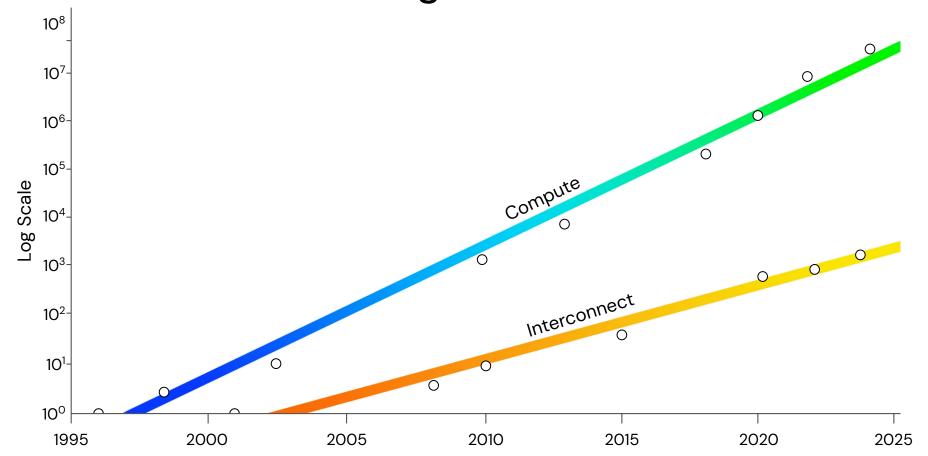




10⁹ Growth in a Decade



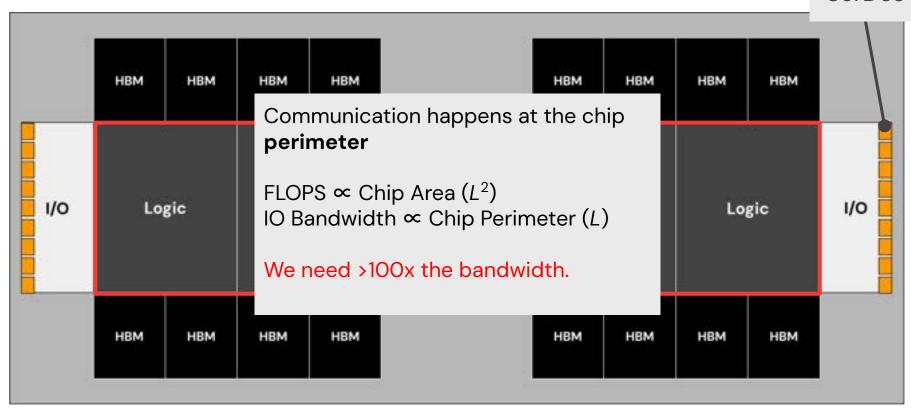
Interconnect Progress Is Too Slow



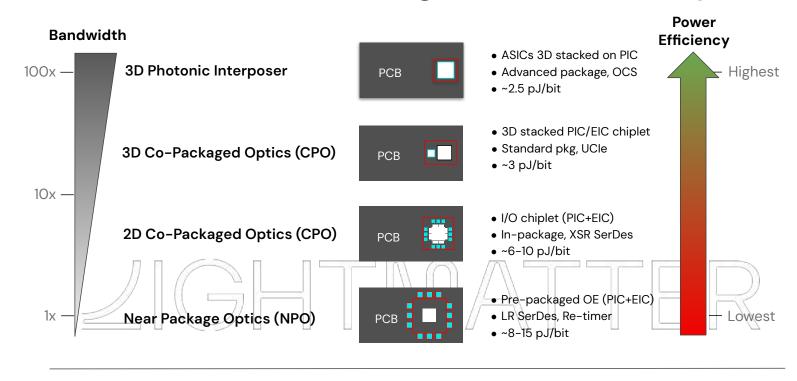
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Challenge: Package Area and Shoreline

SerDes



Photonics Evolution: Moving Closer to the Chip

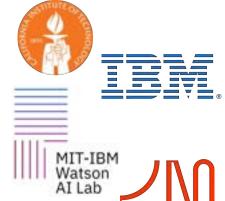




About the Speaker

- PhD from Caltech in Applied Physics Integrated Photonics
 - Some interesting physics around the interactions between optics and mechanics in integrated photonics
- Postdoc & Research Staff at IBM Research Silicon Photonics
 - Developing silicon photonics from early research to production readiness
- Interlude: MIT-IBM Watson Al Lab Al Algorithms Research & Science Program Manager
 - o Fundamental AI research collaboration between industry & academia
- Photonics Architect at Lightmatter Silicon Photonics
 - Back to silicon photonics roots & combine with AI HW requirements
- Director of Laser Development at Lightmatter
 - o Focusing on the critical laser requirements for silicon photonics





Accelerating AI with Light



ZIM

\$850M RAISED

Fidelity Google Ventures Seguoia Spark Capital Viking

T. Rowe Price Matrix Partners SIP Capital MIT Stanford



Mountain View (HQ)



Boston



Toronto

EMPLOYEES



Nicholas Harris, PhD Founder, CEO





Sujatha Wagle VP, Supply Chain Ops



Boon Tan



Praveen Kukkamalla VP, Sales



Founder, Chief Scientist



Ritesh Jain SVP, Engineering & Ops



Beth Keil SVP, People



General Counsel



VP, Cloud Services Sales



Thomas Graham Founder



Bob Turner SVP, Sales & Solution Arch



Steve Klinger VP. Product



Kaushik Patel, PhD VP, Photonics & Si Eng



Israel Kandarian Head of Creative Marketing

311 PAZENTS



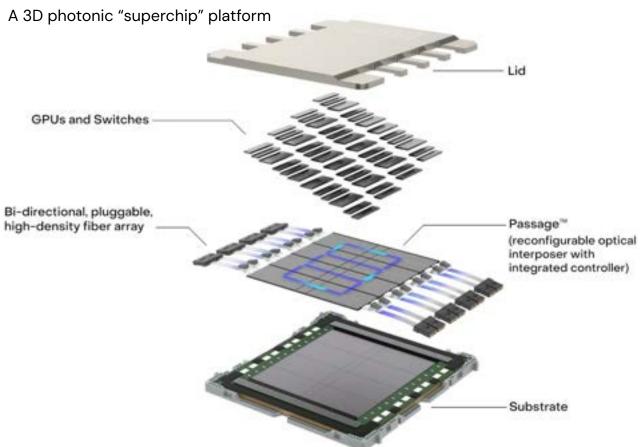
Granted & Pending

Passage™ M Series

A 3D photonic "superchip" platform

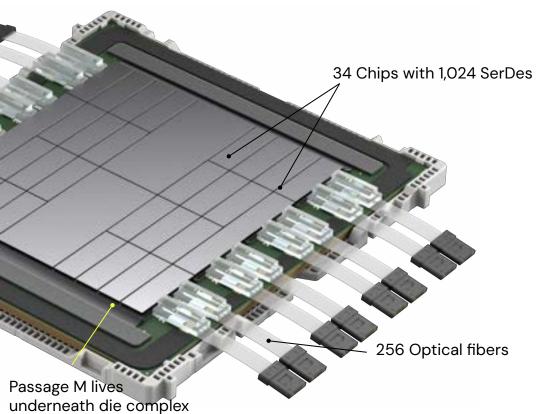


Passage™ M Series



Passage™ M Series

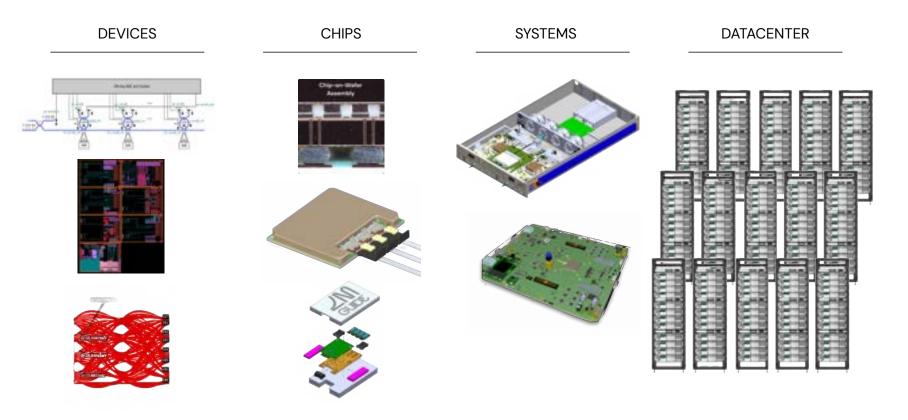
Photonic interposer reference platform



Specifications		
Bandwidth (Tx + Rx)	Up to 114 Tbps	
# of SerDes	1024	
Silicon die Complex	4,000 mm ²	
Power delivery	>1.4 W/mm² density	
Fibers	256	
Redundancy	Optical circuit switching	
Substrate Form Factor	91x85mm	

Enables 114 Tbps total bandwidth.

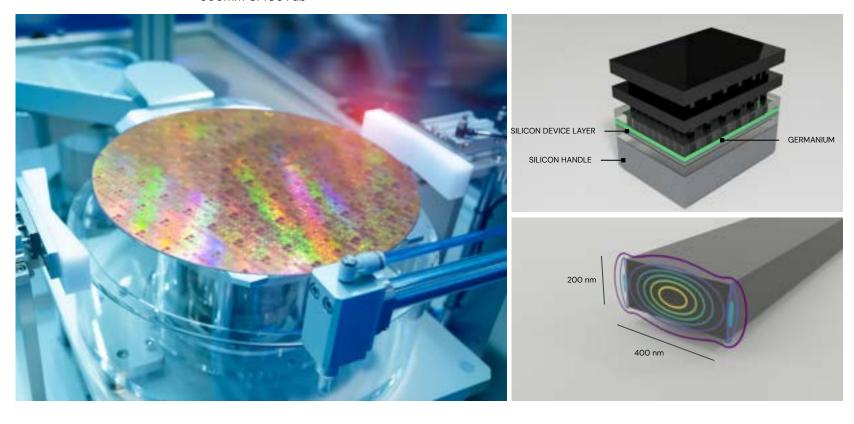
Engineering Capabilities: Rings → Racks



DFX for Photonics Interconnect: Device

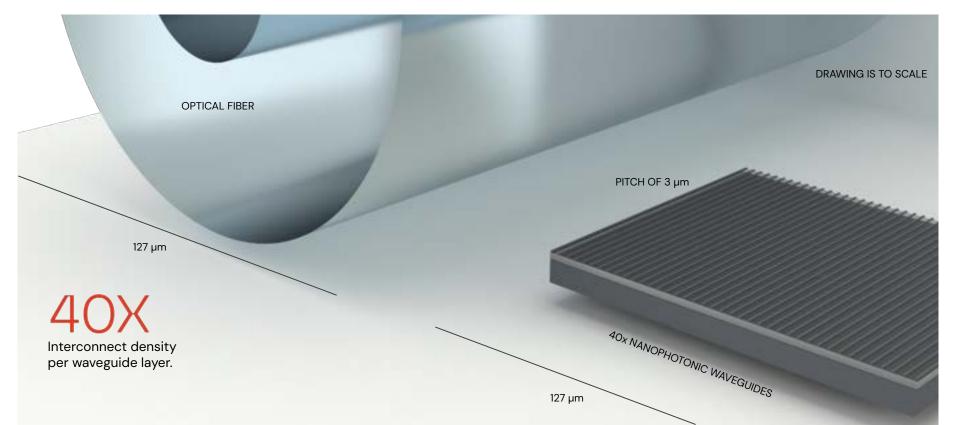
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300mm CMOS Fab

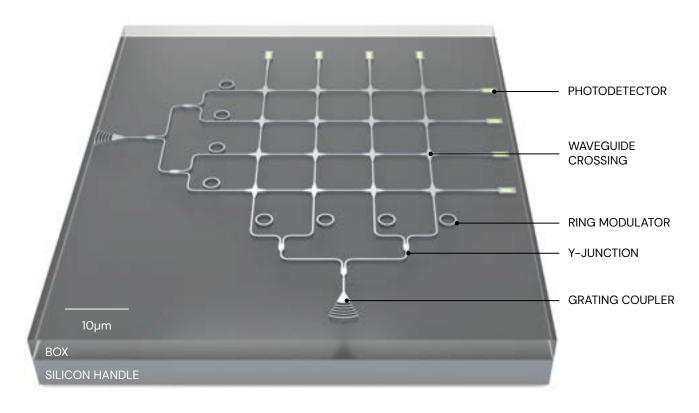


A Sense of Scale

Optical fibers versus nanophotonic waveguides

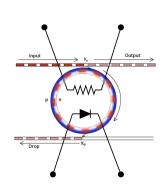


What does silicon photonics look like?

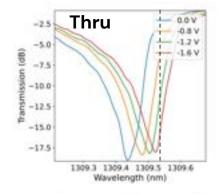


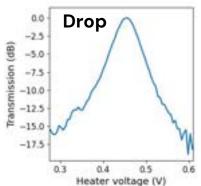
The heart of the engine: silicon microrings

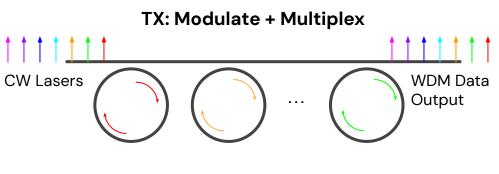
Ultra-compact, high-speed, WDM-friendly

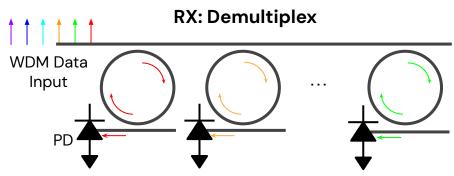


Resistive heater for tuning Depletion PN junction for modulation





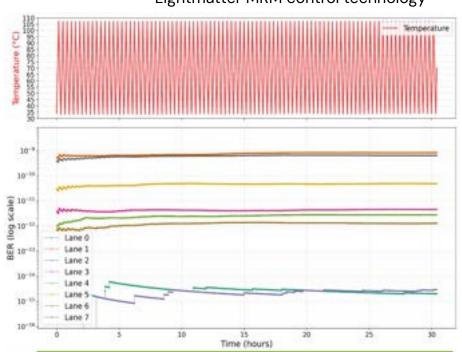




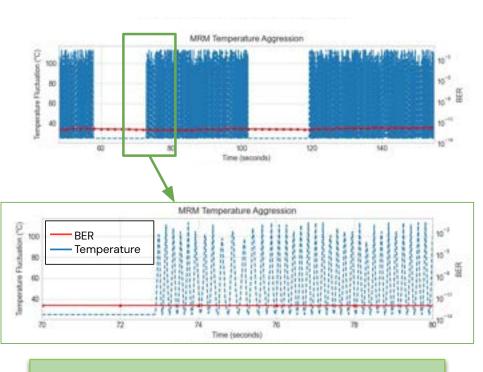
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Rock-solid MRMs in extreme thermals

Lightmatter MRM control technology



Measured robustness against 25 →105→25°C (ΔT=80°C) repeated temperature cycling

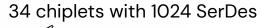


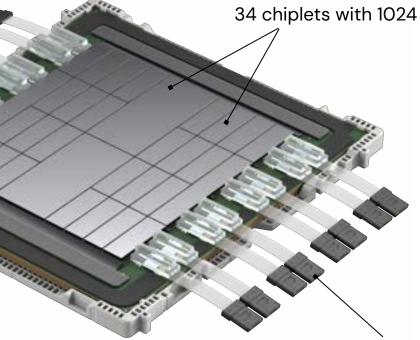
Also robust against rapid 800°C/s temperature change, using an on-die heater aggressor

DFX for Photonics Interconnect: Package

Package Level DFX Challenges

Chip & 3D Packaging Yield, Photonics & Electronics Integration, Design for Test (Electrical & Optical)





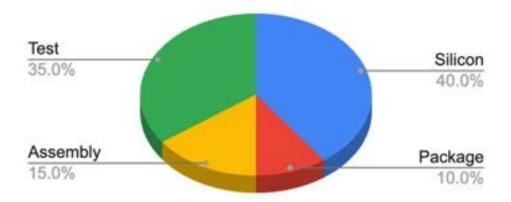
Specifications		
Bandwidth (Tx + Rx)	Up to 114 Tbps	
# of SerDes	1024	
Silicon die Complex	4,000 mm ²	
Power delivery	>1.4 W/mm² density	
Fibers	256	
Redundancy	Optical circuit switching	

256 optical fibers High Precision Alignment, Fiber Attach Yield **Package Thermals** SI & PI Reliability

SPAT Costs and the Need for continued Innovation

Silicon, Package, Assembly, Test





Note: Graph shown for demonstration purposes only

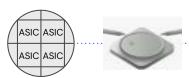
For SiPho Relative Packaging, Assembly and Test (PAT) cost % is increasing

PAT cost challenges in SiPho:

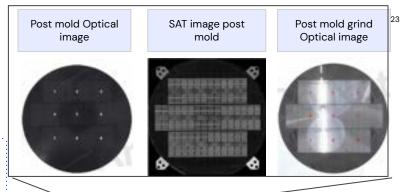
- In assembly: fiber attach yields
- 2. In test: test times are much higher

DFM/DFT-driven product architecture is must for high volume SiPho manufacturing and cost reduction 2IGHTMATTER

M1000 How it's built.



ASIC





Wafer Test

TSV Reveal

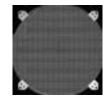
RDL and bumping

CoW reflow: PIC wafer (TSV) to ASIC attach

Wafer level underfill, mold and grind

Wafer dicing









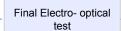






ASIC





Fiber attach with real time optical test

Package e-test (Known good PKG)



Post substrate attach reflow

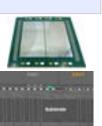












LM Packaging, Test, Quality and Reliability Methodology

Concept/Development

- SI/PI
- Substrate Design
- Design for manufacturing/Reliability
- Thermal analysis
- Mechanical Design/Analysis
- Optical Analysis

Assembly/Test

- 2D and 3D Heterogeneous Integration & process dev.
- Wafer Electrical Sort and Optical Characterization
- Wafer and component test points through the process flow

- Reliability/Validation
- Electrical and Compliance Tests ESD, Latch Up, EMI/EMC
- Package/Environmental TC, UHAST, HTS, S/V, Fiber Integrity
- Operational HTOL
- Failure rate and Lifetime prediction













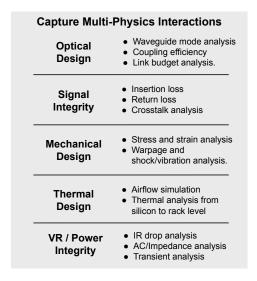


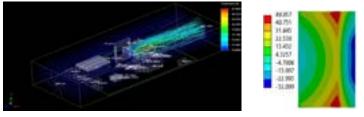


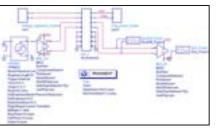


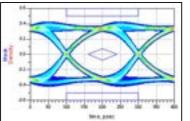
Analysis and Lab Validations

Deliver an **error free** and **high quality design**Model **validation** with lab experiments
Scale **reliable** solutions to High Volume Manufacturing







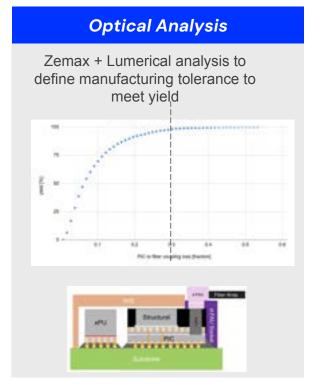




Thermal, Mechanical, and Optical Analysis

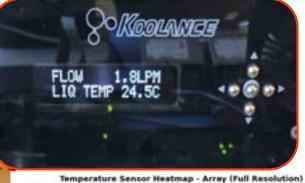
Mechanical Analysis Warpage analysis for to optimize fiber attach manufacturing Model Measurement HT. 40.4 -PH.R. 1016.3

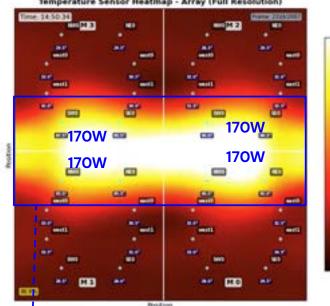
Thermal Analysis Heat transfer based design rule definition for 3D Heterogeneous Integration



Power delivery and //
thermal load

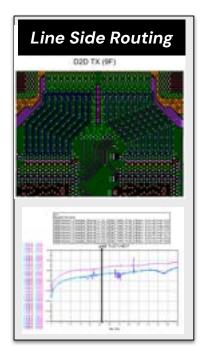


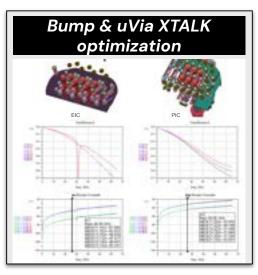


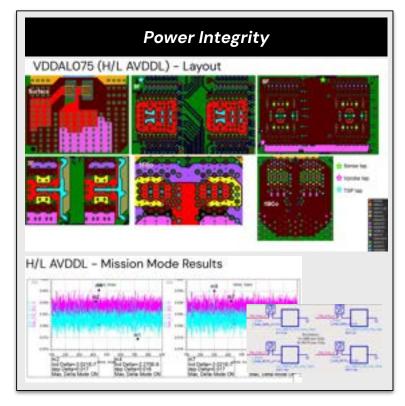


369mm² thermal test chip, power density 1.47W/mm². Passage TSVs support >2.5A/mm².

SI, PI + Packaging Design

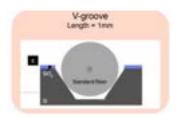




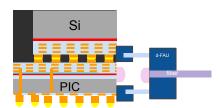


Fiber Attach Methods

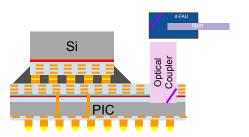
Traditional FAU



Lens based edge attach



Wafer Level Optical coupler



V-Groove based Fiber Attach Methods	Lens based: Detachable fiber attach	LM Focus: Detachable fiber attach
Package level assembly (interface on die edge)	Package level assembly (interface on die edge)	Wafer level assembly and test compatible
Not compatible with 3D Arch	Compatible with 3D Package Arch	Compatible with 3D Package Arch
XPU to OE D2D: Standard Package	XPU to OE D2D: Standard & Adv. Package	XPU to OE D2D: Standard & Adv. Package
Passive or Active alignment	Active alignment	Passive or Active alignment
Test with FAU after package assembly	Test with FAU after package assembly	Test with FAU at wafer level
FAB: GF only	FAB: GF & TSMC	FAB: GF & TSMC
Serviceability: No	Serviceability: Yes	Serviceability: Yes
Limited scalability to HVM	Scalability to HVM	HVM scalable solution

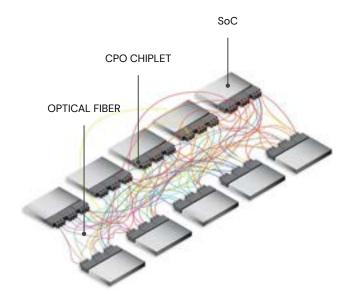
LM driving strong ecosystem partnership to bring detachable FAUs to HVM scale



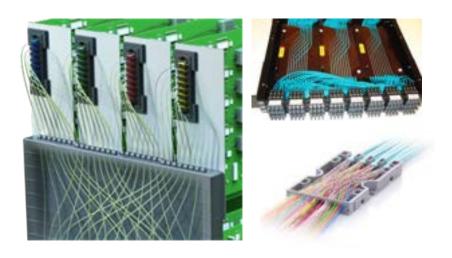
DFX for Photonics Interconnect: System

System Level DFX Challenges

SERVICEABILITY, MANUFACTURABILITY, YIELD

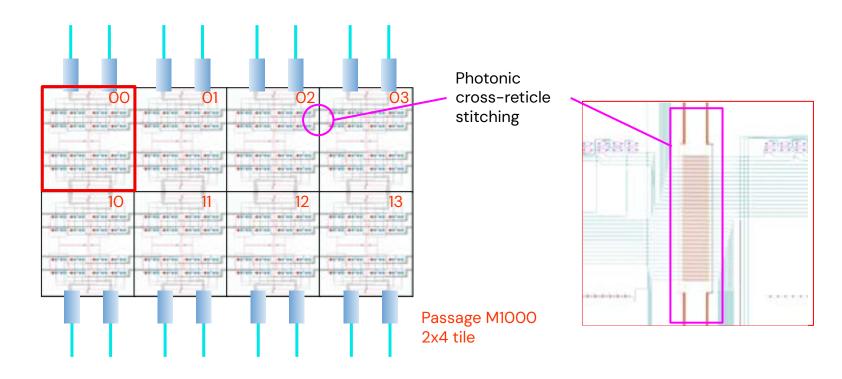






Reconfigurable connectivity

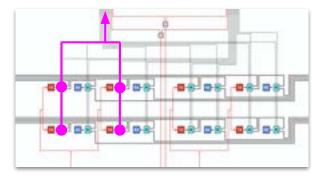
A dynamic, programmable optical fabric in the 2x4 tile design

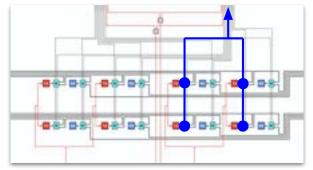


Resilience through optical circuit switching

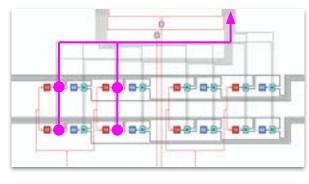
Fiber attach redundancy allows users to route around failures

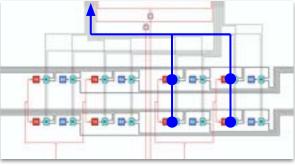
Option A (default):





Option B (backup):

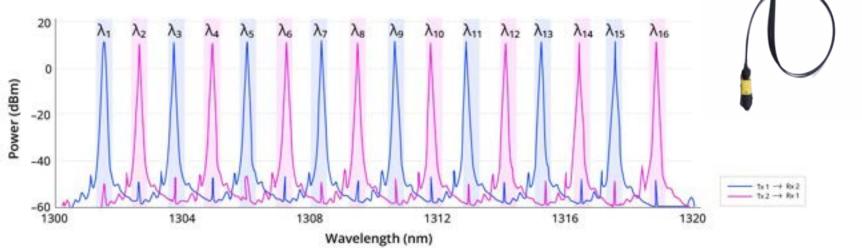




Guide™: External WDM laser

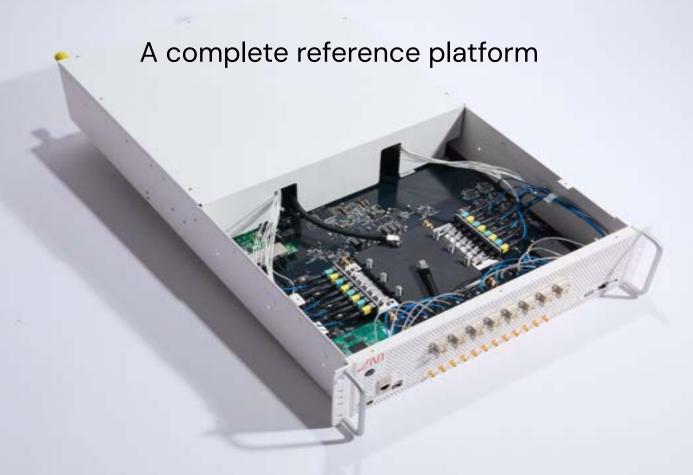
Up to 16 wavelengths per fiber, 200 GHz grid 16 fiber output

Optimized for microring modulator Tx architectures

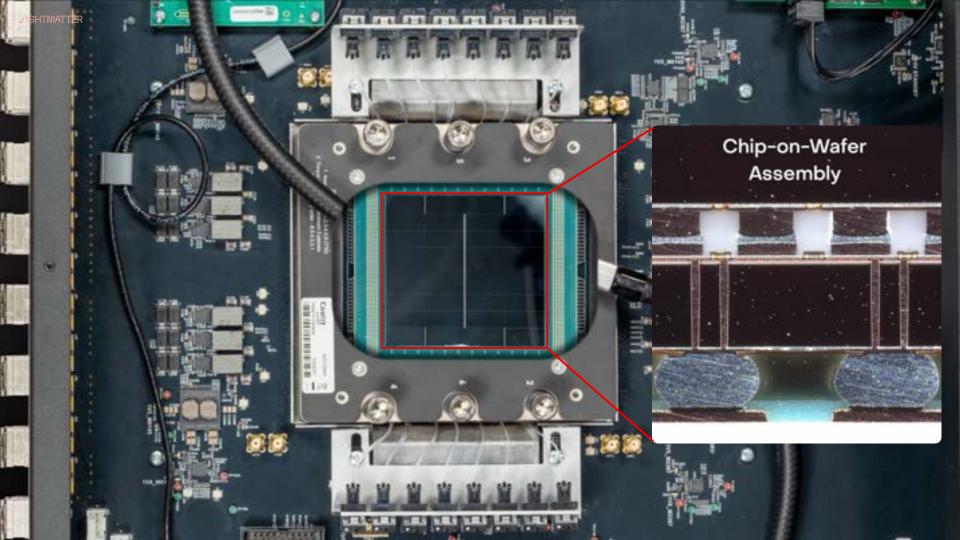










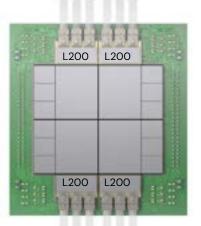


Lightmatter 3D CPO Product and Ecosystem

Customer ASIC Multiple fabs with UCle IP Passage™ EIC **Partners ZIGHTMATTER** Passage™ PIC Multiple Detachable Fiber Coupler **Suppliers** Guide™ Light Engine 2M(16λ, 100 mW/fiber)







- Global ecosystem
- High-volume readiness
- Quality and reliability





Key Takeaways

- Transition from traditional manufacturing to specialized skills
- Working cross-functionally is key make connections!
- Opportunities to go **broad** or **deep**
- New industries provide new opportunities

